



Title of Change:	Interface and Bus Switch Back End Site and Material Change	
Proposed first ship date:	7 February 2019 or earlier upon customer approval	
Contact information:	Contact your local ON Semiconductor Sales Office or <logic.fpcn@onsemi.com>	
Samples:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com> Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Phine.Guevarra@onsemi.com>	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>	
Change Part Identification:	Affected product will be marked with new marking style	
Change Category:	<input type="checkbox"/> Wafer Fab Change <input checked="" type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____	
Change Sub-Category(s):	<input type="checkbox"/> Manufacturing Site Addition <input checked="" type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input checked="" type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input checked="" type="checkbox"/> Shipping/Packaging/Marking <input checked="" type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____	
Sites Affected:	ON Semiconductor Sites: ON Seremban, Malaysia	External Foundry/Subcon Sites: Subcon Thailand
Description and Purpose:		
Qualify a new subcon site to increase capacity.		
Material to be changed	Before Change (Existing flow)	After Change (new flow)
Assy Site	ON Seremban Malaysia	Subcon Thailand
Mold Compound	MC SUMITOMO EME-G600FB	Molding Compound G600
Lead frame	AG STRIPE OVER D005	LF; PPF+ME2; US8; DAP 59x38
Die Attach	DA EN4370K3 SNAP CURE NON-C	Non-Conductive DAF, HR-5140
Plating	100% Sn	Preplated
Product marking change	<p>MARKING DIAGRAM</p> <p>LR =Device Code, M = D ate Code, Dot(.)=Lead Free Package</p>	<p>MARKING DIAGRAM</p> <p>XXXX=Device Code, A= Assy location, L= Lot Code,Y=Year Code, W =Week Code</p>



Reliability Data Summary:

QV DEVICE NAME: NLV7WBD3125USG

RMS: S44394

PACKAGE: US 8

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta= 125°C	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -65°C to + 150°C	1000 cyc	0/80
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/80
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/80
PC	J-STD-020 JESD-A113	MSL 1 @ 260°C		0/240
SD	JSTD002	Ta = 245C, 10 sec		0/ 15
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30

QV DEVICE NAME: NLV9306USG

RMS: P44400 ; S48494

PACKAGE: US 8

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta= 125°C	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -65°C to + 150°C	1000 cyc	0/80
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/80
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/80
PC	J-STD-020 JESD-A113	MSL 1 @ 260°C		0/240
SD	JSTD002	Ta = 245C, 10 sec		0/ 15
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30

Electrical Characteristic Summary: Electrical characteristics Available upon request.

List of Affected Parts:

Part Number	Qualification Vehicle
PCA9306USG	NLV9306USG
7WBD3125USG	NLV7WBD3125USG
7WBD383USG	NLV7WBD3125USG
7WBD3306USG	NLV7WBD3125USG
7WBD3126USG	NLV7WBD3125USG
7WBD3305USG	NLV7WBD3125USG

Japanese translation of the notification starts here.
通知の日本語訳はここから始まります。

Note: The Japanese version is for reference only. In case of any differences between the English and Japanese version, the English version shall control.

注：日本語版は参照用です。英語版と日本語版の違いがある場合は、英語版が優先されます。



信頼性データの要約:

QV 素子名: NLV7WBD3125USG

RMS: S44394

パッケージ: US 8

テスト	仕様	条件	間隔	結果
HTOL	JESD22-A108	Ta= 125°C	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -65°C to + 150°C	1000 cyc	0/80
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/80
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/80
PC	J-STD-020 JESD-A113	MSL 1 @ 260°C		0/240
SD	JSTD002	Ta = 245C, 10 sec		0/ 15
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30

QV 素子名: NLV9306USG

RMS: P44400、S48494

パッケージ: US 8

テスト	仕様	条件	間隔	結果
HTOL	JESD22-A108	Ta= 125°C	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -65°C to + 150°C	1000 cyc	0/80
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uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/80
PC	J-STD-020 JESD-A113	MSL 1 @ 260°C		0/240
SD	JSTD002	Ta = 245C, 10 sec		0/ 15
RSH	JESD22- B106	Ta = 265C, 10 sec		0/30

電気的特性の要約: 電気的特性の提出は要求に基づきます。

影響を受ける部品の一覧:

部品番号	品質試験用ビークル
PCA9306USG	NLV9306USG
7WBD3125USG	NLV7WBD3125USG
7WBD383USG	NLV7WBD3125USG
7WBD3306USG	NLV7WBD3125USG
7WBD3126USG	NLV7WBD3125USG
7WBD3305USG	NLV7WBD3125USG



Appendix A: Changed Products

Product	Customer Part Number	Qualification Vehicle
7WBD3125USG		NLV7WBD3125USG
7WBD3126USG		NLV7WBD3125USG
7WBD3305USG		NLV7WBD3125USG
7WBD3306USG		NLV7WBD3125USG
7WBD383USG		NLV7WBD3125USG
PCA9306USG		NLV9306USG